

Form PTO 1449  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.  
212881US2SERIAL NO.  
NEW APPLICATION

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Eiji YOSHIDA

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GROUP



## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	Mario PANICCIA, et al., "NOVEL OPTICAL PROBING TECHNIQUE FOR FLIP CHIP PACKAGED MICROPROCESSORS", INTERNATIONAL TEST CONFERENCE 1998, IEEE, pp 740-747
	AX	T.M. EILES, et al., "OPTICAL INTERFEROMETRIC PROBING OF ADVANCED MICROPROCESSORS", INTERNATIONAL TEST CONFERENCE 2000, 5 pages
	AY	
	AZ	

Examiner **J. MONDT**Date Considered **May 9 '02.**

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

U.S. PTO  
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